

**Search Notes**

Application/Control No.

10/644,900

Examiner

Maikhanh Nguyen

Applicant(s)/Patent under  
Reexamination

DUNCAN ET AL.

Art Unit

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	512 513	8/16/2007	MK
	517 541	8/16/2007	MK
382	186	8/16/2007	MK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Name Search	5/31/2007	MK
NPL (IEEE)	5/31/2007	MK
West Search (USPAT, USPGPub, EPO, JPO, DERWENT) - See Search History Printout	8/16/2007	MK